

WPI

Center for Imaging and Sensing (CIS)

Raunak Borwankar, Ian Costanzo, Gene Bogdanov,
Sasidhar Tadanki, Reinhold Ludwig

ECE Department

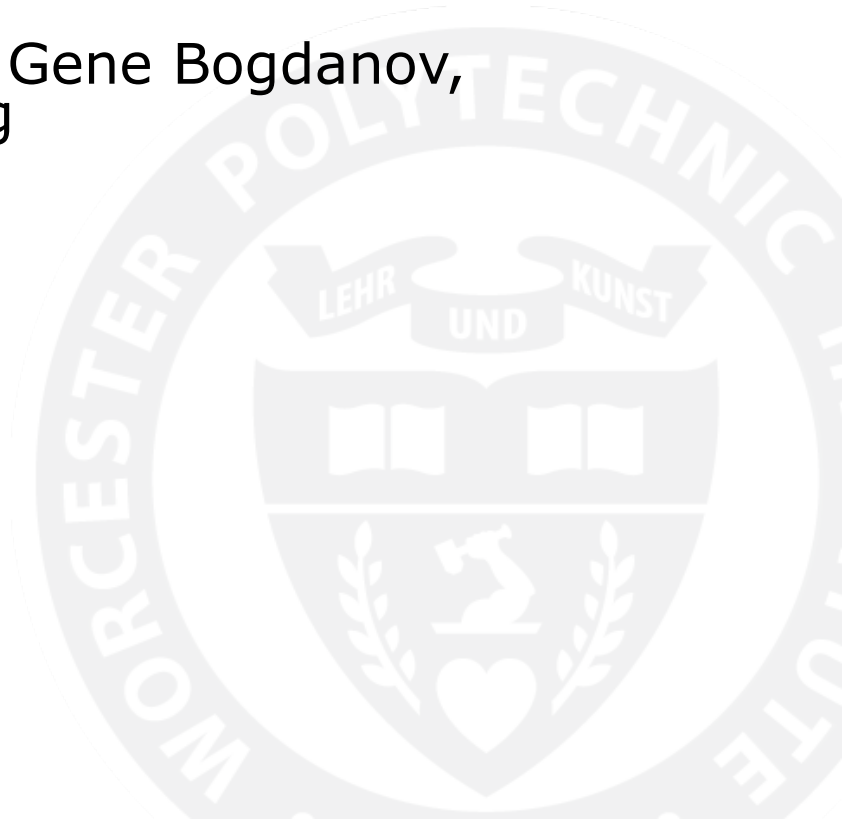
Worcester Polytechnic Institute

100 Institute Road

Worcester, MA 01609

Phone: 508-831-5231

October 10, 2017



Center Organization

- **Objective**
 - To assist our industrial partners in their quality assurance and imaging requirements
- **What we deliver**
 - Inspection and imaging methodologies
 - Fundamental sensor and instrumentation research
 - Turn-key prototype system development
 - Circuit design, simulations, layouts
- **Organization**
 - Two full-time ECE faculty
 - Funded graduate research assistants
 - ECE software/hardware tools, shop resources

Approach

- Regular meetings with our partners
 - Company-specific research updates
 - Demonstration of prototypes
 - Presentations by undergraduate/graduate project students
- Use of industry standard tools
 - HFSS, ADS, Matlab, SolidWorks, etc.
- Dissemination of research
 - Research reports
 - Conference/journal publications
 - Student theses

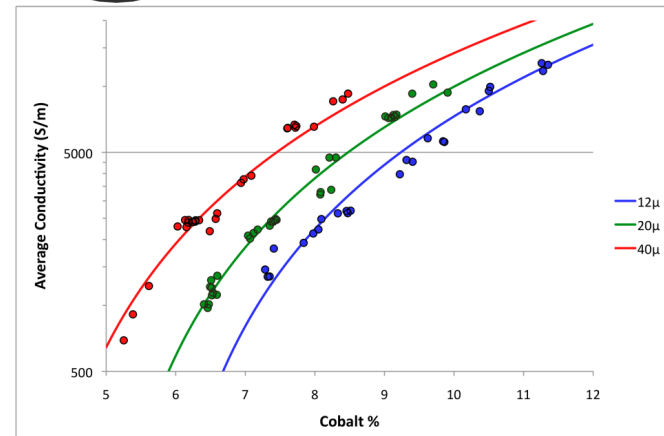
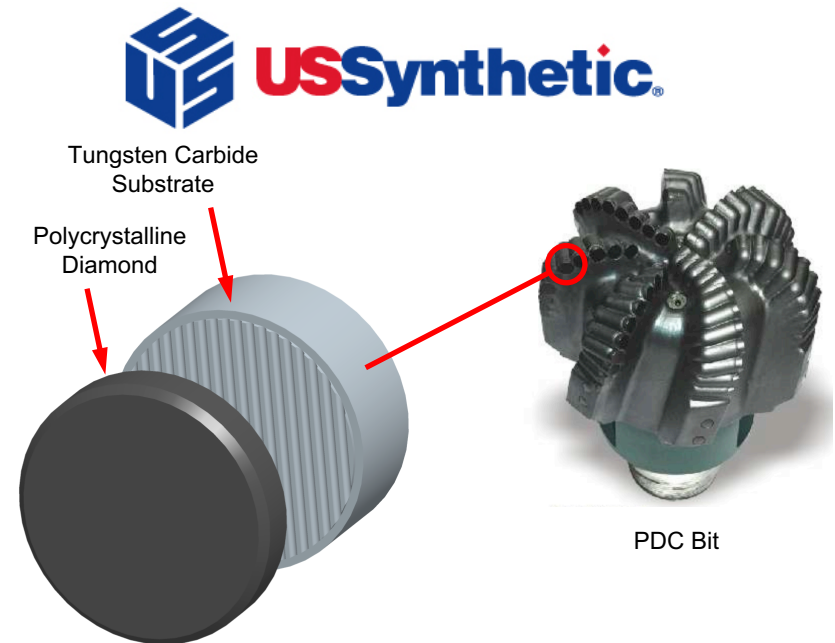
1st Example: Electrical Impedance Tomography (EIT) of Polycrystalline Diamond Cutters

- **Problem description**

- Have to characterize cutter performance nondestructively
- Need to detect hidden defects in a cost-effective way

- **Approach**

- Measure electrical conductivity
 - Diamond table conductivity depends on residual metal content
 - Metal content is correlated with cutter performance characteristics
- Localized conductivity measurement can detect defects (metal-rich zones, cracks)



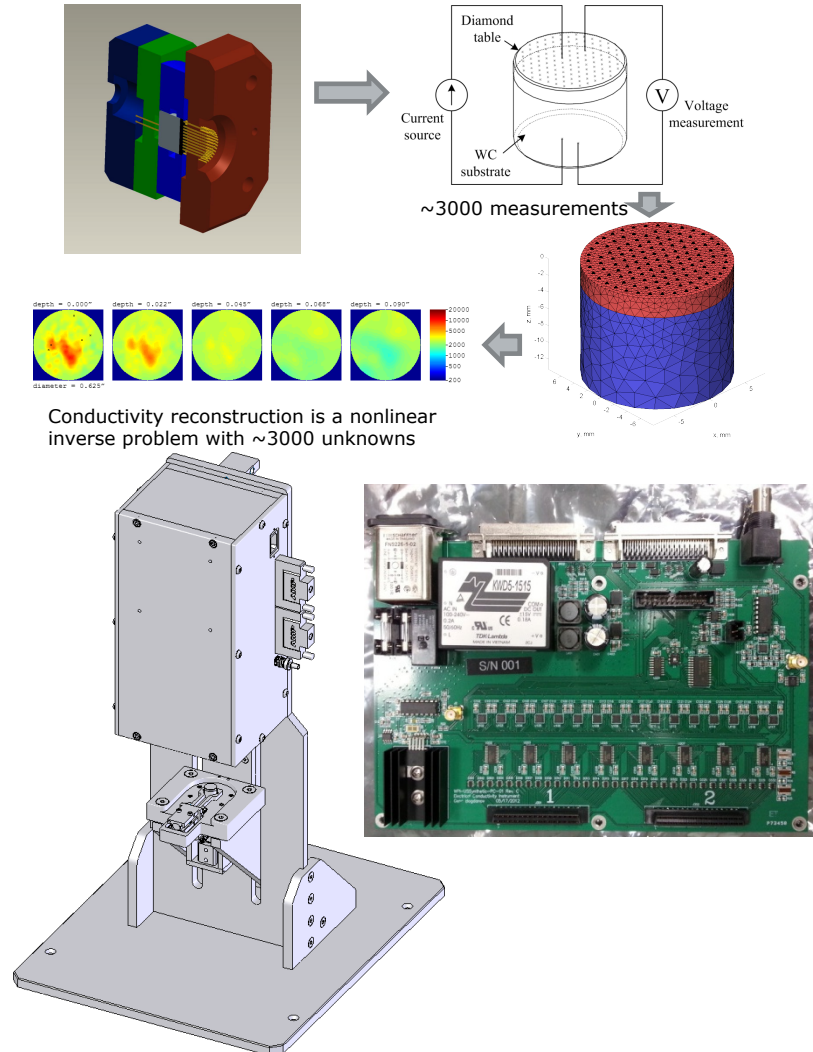
EIT System Development

- **What we built**

- EIT data acquisition system
 - Sensor with 120+2 pogo pins
 - Analog front end (custom PCB)
 - Pneumatic system for placing cutter in contact with the sensor
 - Machine vision system for diamond table thickness measurement
- Custom-developed 3D EIT software
 - FEM forward solver
 - GPU-accelerated iterative inverse solver

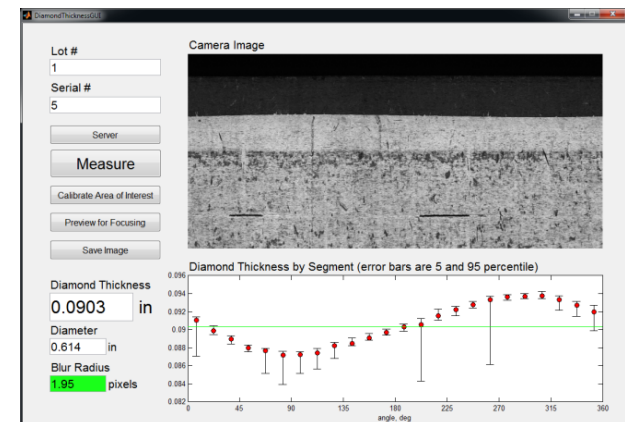
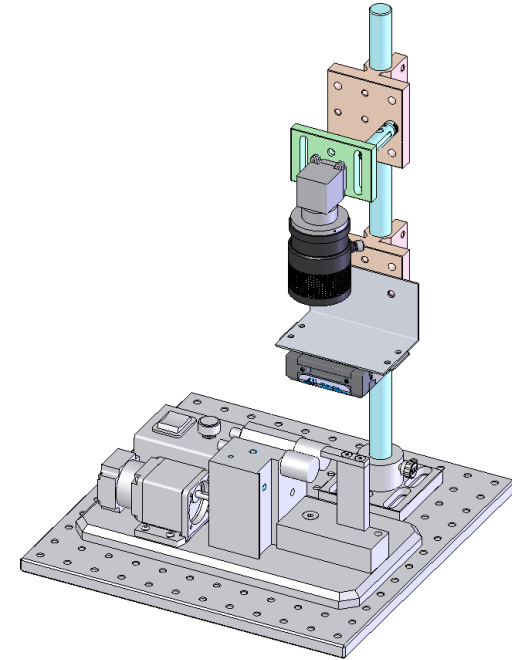
- **Outcomes**

- Two machines in industrial use for more than 5 years
- Conductivity dataset acquired and reconstructed in 5 sec
- 1 journal paper, 3 conference papers
- 1 patent granted



2nd Example: Machine Vision System for Diamond Thickness Measurement

- **Problem description**
 - Diamond cutter EIT requires diamond thickness for quantitative conductivity measurements
- **What we built**
 - Machine vision system using specular reflection contrast
 - Cutter is rotated by an existing roller system
 - Full rotation is detected by image correlation
 - Blur radius measurement for focusing
- **Outcome**
 - One prototype in use and coupled to one of the EIT machines



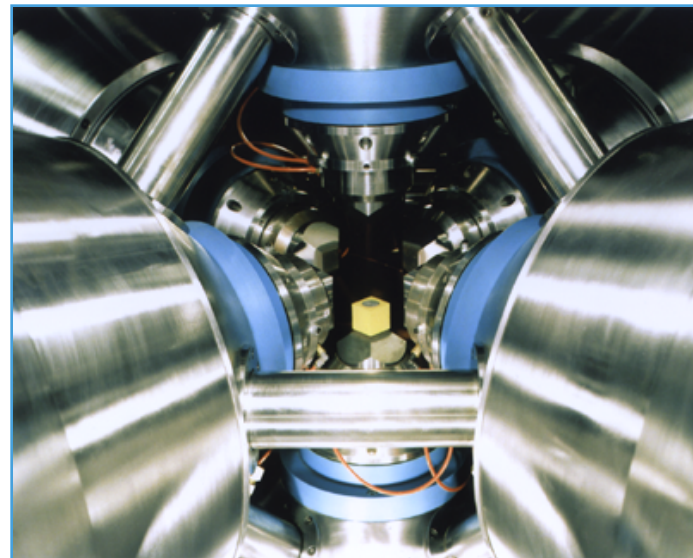
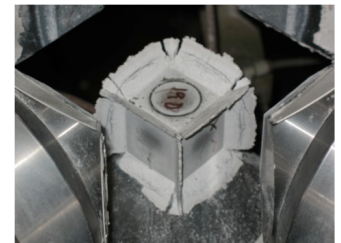
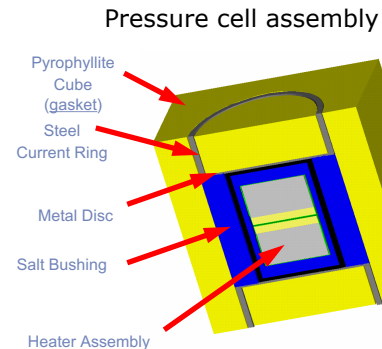
3rd Example: High-Pressure Gasket Moisture Content Measurement

- **Problem description**

- Soft material is used as a gasket and pressure transmission medium
- Excess moisture gasket can cause failure during decompression
 - Potential catastrophic damage to press anvils
- Need a nondestructive method of monitoring gasket moisture content

- **Approach**

- Electric RF field/moisture interaction



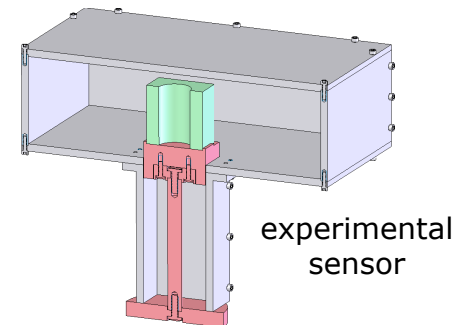
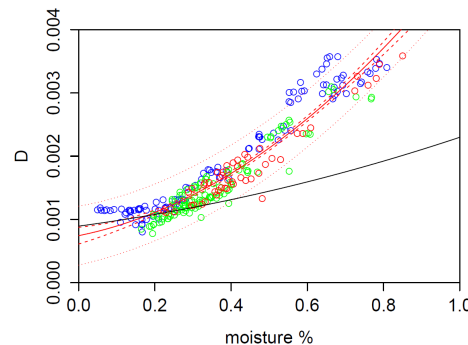
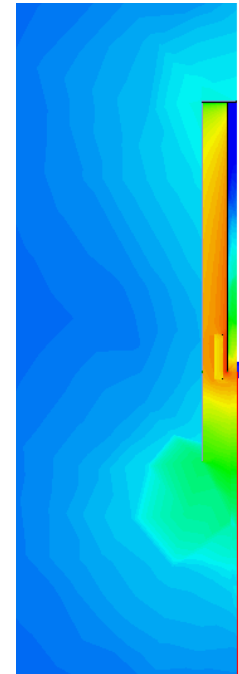
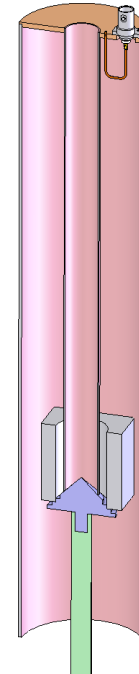
High-Pressure Gasket Moisture System

- **What we built**

- Coaxial resonator sensor
- Sample loader
- Rapid moisture content estimation software
- Experimental multimode cavity sensor

- **Outcomes**

- 5 moisture meters installed at our industrial partner
- 3 QNDE papers
- 1 patent application filed

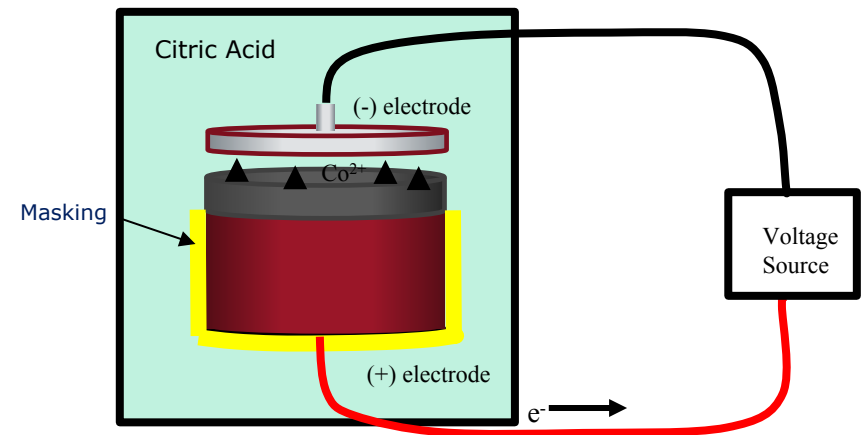


4th Example: Electrochemical Leaching of Polycrystalline Diamond



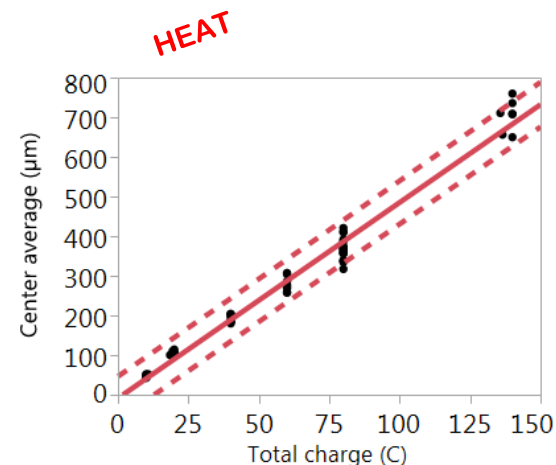
- **Problem description**

- Metal must be removed from polycrystalline diamond to a certain depth to meet performance specifications
- Existing process using HF-HNO₃ mix is slow, inconsistent, prone to yield issues, and dangerous
- Our partner needs a replacement process



- **Approach**

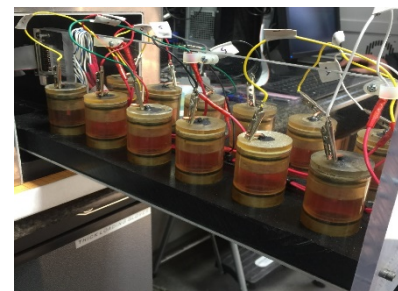
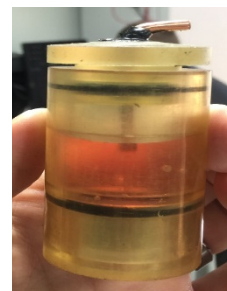
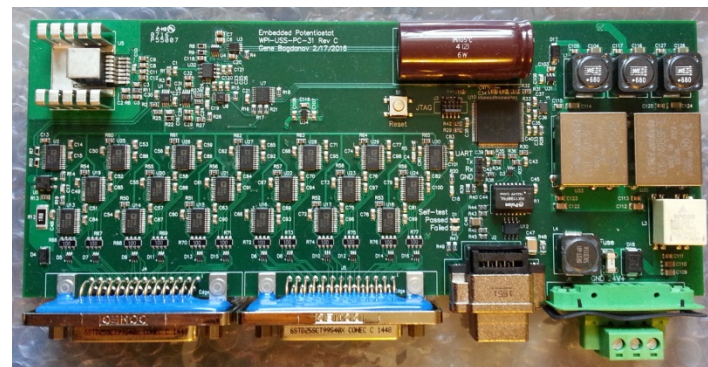
- Electrochemical metal removal
- Amount of metal is related to accumulated charge
- Nontoxic chemicals



Electrochemical Leaching System

• What we built

- Multichannel (48-channel) potentiostat
 - Applies voltage to cells
 - Measures current in each leaching cell
 - Accumulates charge
 - Stops current when reaching calculated charge level
 - Ethernet connectivity
- Central control software for large number of potentiostats
- Individual cutter cells (jointly developed)
- Oven for heating cells (jointly developed)



• Outcomes

- 6 potentiostat prototypes deployed (24, 32 and 48-channel versions)
- Large amount of data collected
- 1 patent application filed

Channel	Current, μ A	Charge, C	Time, hr	Final Charge, C
1	0.00	1.0000	0.5547	0.5547
2	0.00	1.0001	0.6936	0.6936
3	-0.01	4.1028e	0	0
4	0.00	3.9229e	0	0
5	-0.03	3.8014e	0	0
6	-0.01	3.7899e	0	0
7	0.00	3.7352e	0	0
8	-0.01	3.1109e	0	0
9	0.00	3.4400e	0	0
10	-0.01	3.4537e	0	0
11	-0.02	3.4252e	0	0
12	0.01	2.8585e	0	0
13	0.00	2.9745e	0	0
14	-0.01	3.0579e	0	0
15	0.00	3.0062e	0	0
16	0.02	2.9533e	0	0

Channel	Current, μ A	Charge, C	Time, hr	Final Charge, C
1	-0.01	2.4000e	0	0
2	0.00	1.0019	0.1392	0.1392
3	-0.01	2.3096e	0	0
4	0.01	1.6940e	0	0
5	-0.01	1.8992e	0	0
6	0.01	1.9188e	0	0
7	-0.00	1.8679e	0	0
8	-0.02	1.2945e	0	0
9	-0.01	1.6500e	0	0
10	-0.00	1.7077e	0	0
11	-0.01	1.7773e	0	0
12	-0.01	1.8607e	0	0
13	-0.02	1.2355e	0	0
14	0.01	1.3682e	0	0
15	0.01	1.2385e	0	0
16	0.01	1.2185e	0	0

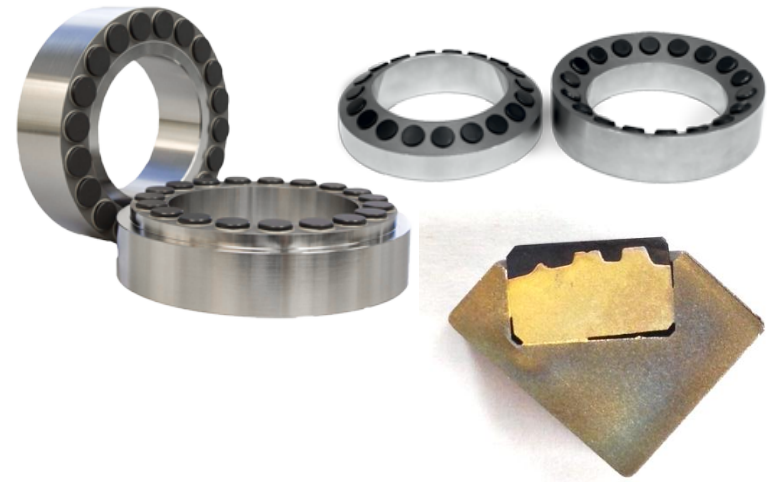
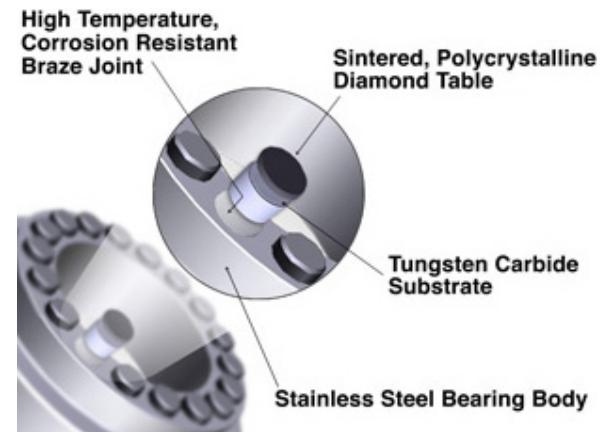
5th Example: Lock-in Thermography for Bearing Braze Joint Inspection

- **Problem description**

- Bearings for well drilling use polycrystalline diamond
- Diamond-tipped inserts are brazed into the bearing body
- Poor braze joints cause premature failure
- Need a nondestructive braze joint inspection

- **Approach**

- Low braze joint area results in weak thermal contact with the body
- Measure thermal conduction from inserts to the body via lock-in thermography



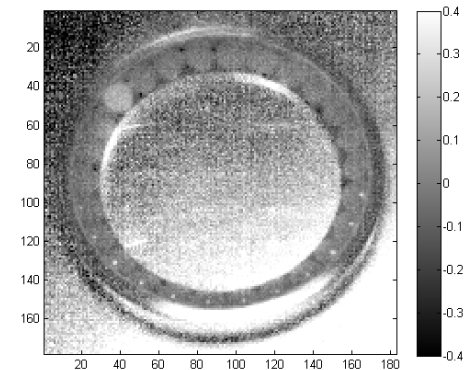
Bearing Braze Joint Inspection System

- What we built

- Lock-in thermography system
 - Heating by 1000 W halogen lamp
 - Sinusoidal modulation of lamp output
 - IR camera images surface temperature evolution over time
- Software to compute phase shift between heat source and temperature
 - Robust measure of thermal diffusivity

- Outcomes

- 1 prototype constructed
- Successfully detected 1 bad braze joint in a limited number of samples



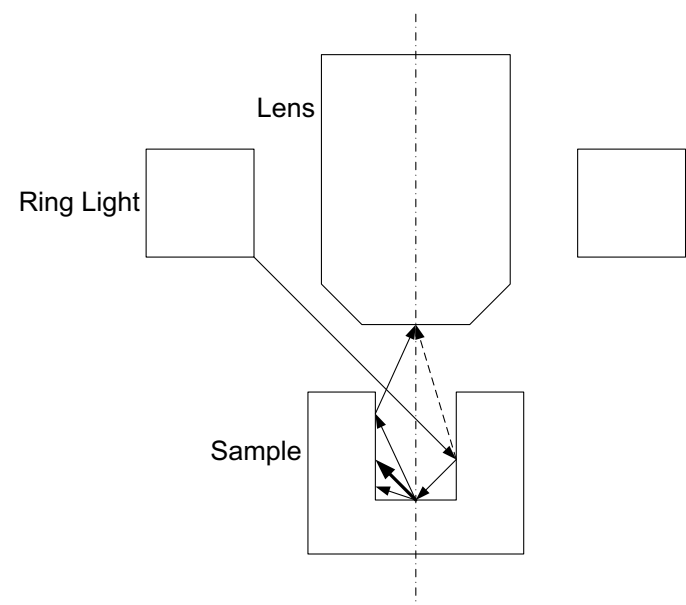
6th Example: Bore Inspection

- Problem description

- Need to detect surface-breaking pores with resolution of 100 μ m in diameter on bore wall

- Approach

- Machine vision
- Specular reflection contrast
 - Bore wall strongly reflective
 - Pores less reflective
- Fast, low cost
 - No sophisticated part manipulation (e.g. rotation-translation)



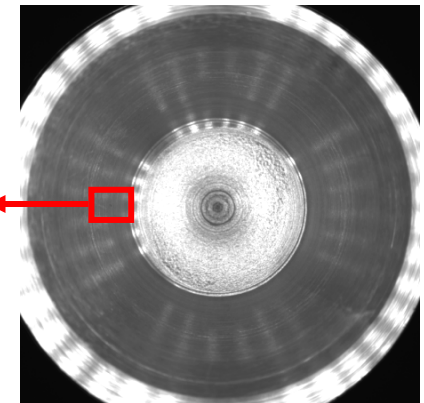
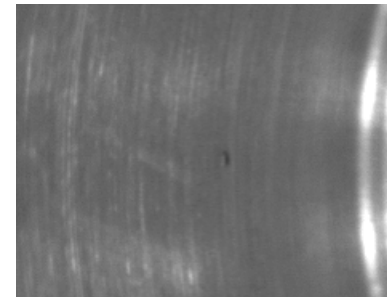
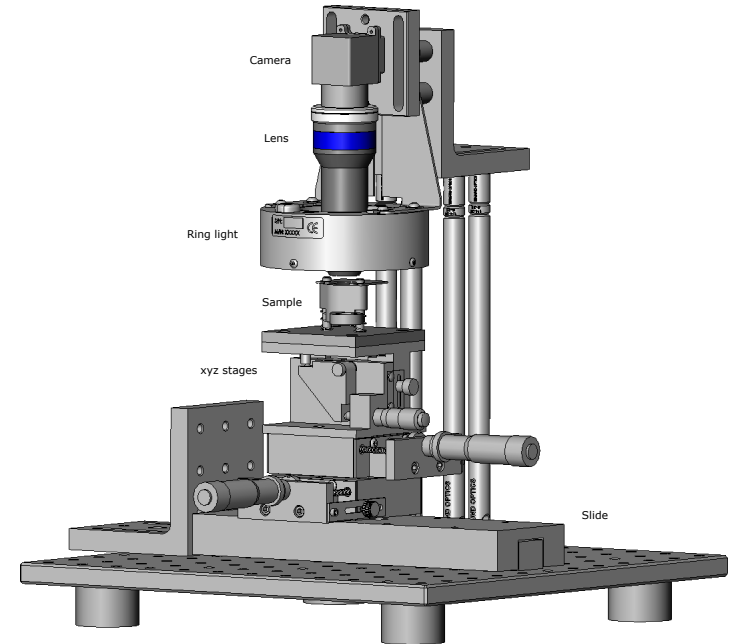
Bore Inspection System

- What we built

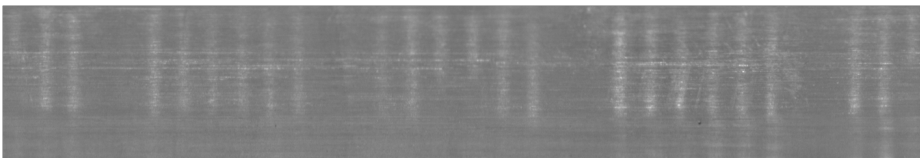
- Imaging system
 - High-resolution 5 MP camera
 - Wide angle, short standoff lens
 - Ring light illumination
- Sample loader
- Image processing software
 - Bore wall unwrapping
 - Defect detection

- Outcomes

- Simulated pores detected on wide-bore (0.452") parts
 - Parts modified: rough bore bottom
- Revision is under development to improve contrast
 - Axial illumination

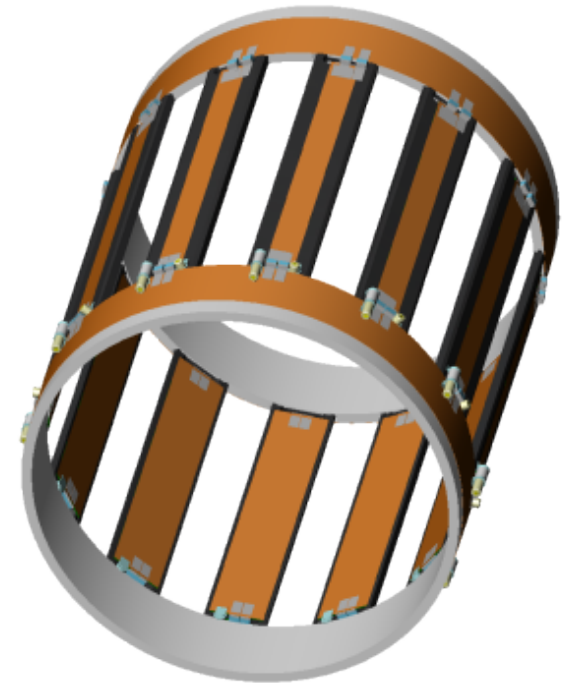


← unwrapped bore



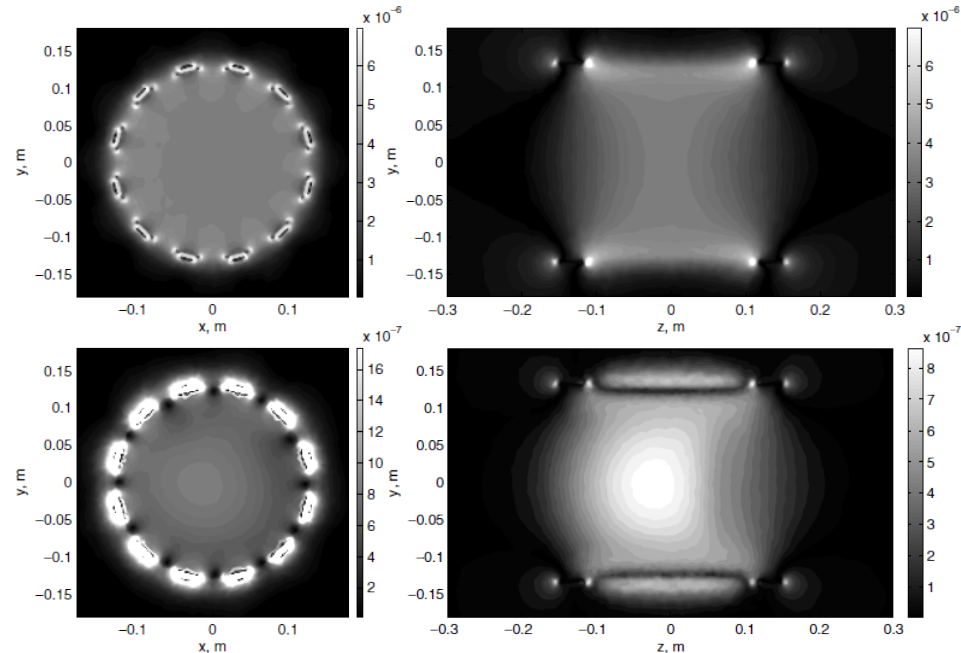
7th Example: Magnetic Resonance Imaging Dual-Tuned Head Coil

- **Problem description**
 - Demand for dual-tuned clinical MRI transmit/receive head coils for sodium (^{23}Na) and hydrogen (^1H) at 3T for stroke imaging
 - Wide frequency separation between ^{23}Na at 34 MHz and ^1H at 128 MHz
 - Higher frequency circuits inhibit the performance at the lower frequency, which is most critical
- **Approach**
 - Experimental coil design
 - Birdcage at low frequency (34 MHz)
 - TEM-like coil at high frequency (128 MHz)

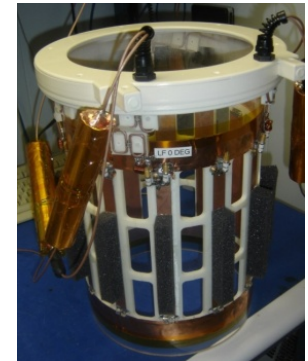


MRI Dual-Tuned Head Coil

- **What we built**
 - Simulated competing coil designs
 - Experimental birdcage-TEM coil
 - Typical dual-tuned birdcage coil
 - Dual-tuned TEM coil
 - Built and tested a prototype birdcage-TEM coil
- **Outcomes**
 - NIH SBIR grant awarded
 - Prototype performed similarly to simulation



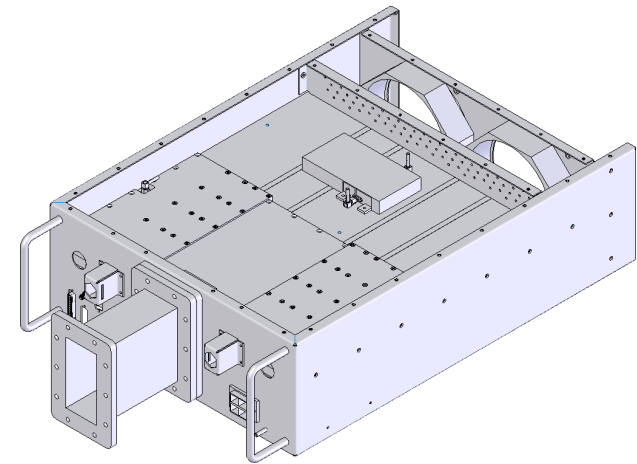
B₁ field with load:
top – 34 MHz (²³Na)
bottom – 128 MHz (¹H)



8th Example: Solid-state 2 kW 2.45 GHz Microwave Generator

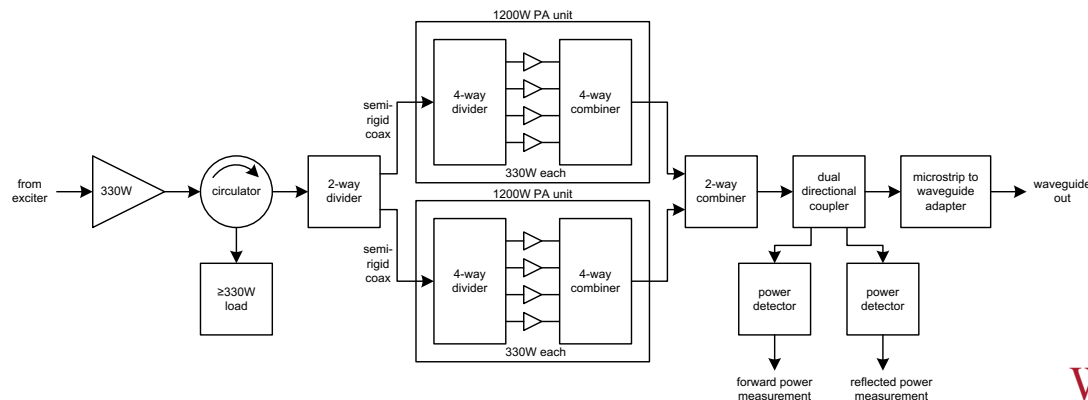
- **Problem description**

- Semiconductor industry looking to replace magnetron MW generators with solid-state versions
 - More controllable and reliable
- Challenges
 - small package (4U rackmount)
 - waveguide output
 - efficient, pulsing capable
 - low cost, short development time



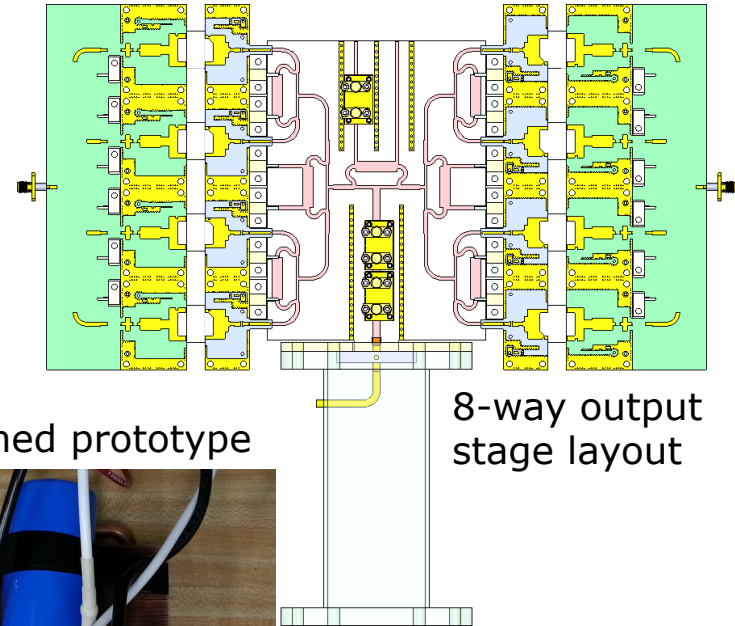
- **Approach**

- Combine outputs of eight 330 W solid-state power amplifier modules

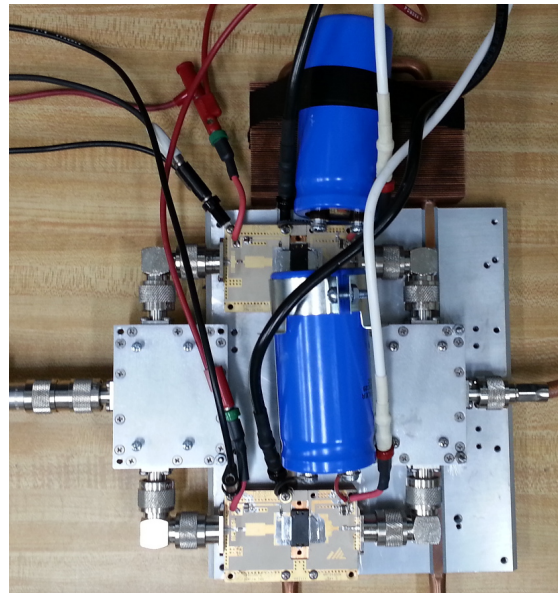


Solid-state Microwave Generator

- **What we did**
 - Designed output stage with custom MW components:
 - power combiners
 - power dividers
 - directional couplers
 - waveguide transition
 - Tested 2-way combined 330 W modules
- **Outcomes**
 - 2-way prototype performed well
 - up to 550 W output
 - no oscillation
 - pulsing capable



2-way combined prototype



custom 2-way combiner

